Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/075,051	WANG ET AL.		
Examiner	Art Unit		
Dienane M. Bayard	2141		

SEARCHED						
Class	Subclass	Date	Examiner			
709	217	10/25/2005	DB			
709	226	10/25/2005	DB			
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INTERFERENCE SEARCHED						
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